

AUTOMOTIVE CURRENT TRANSDUCER HAH1DR 400-S/SP1









Introduction

The HAH1DR family is for the electronic measurement of DC, AC or pulsed currents in high power automotive applications with galvanic isolation between the primary circuit (high power) and the secondary circuit (electronic circuit).

The HAH1DR family gives you the choice of having different current measuring ranges in the same housing (from \pm 200 A up to \pm 900 A).

Features

- Open Loop transducer using the Hall effect
- Unipolar + 5 V DC power supply
- Primary current measuring range up to ± 400 A
- Maximum rms primary current limited by the busbar, the magnetic core or the ASIC temperature T° < +150 °C
- Operating temperature range: -40°C < T° < +125 °C
- Output voltage: full ratiometric (in sensitivity and offset)
- · Compact design.

Advantages

- Excellent accuracy
- Very good linearity
- · Very low thermal offset drift
- Very low thermal sensitivity drift
- · Wide frequency bandwidth
- No insertion losses.

Automotive applications

- Battery monitoring
- Starter Generators
- Inverters
- HEV application
- EV application.

Principle of HAH1DR Family

The open loop transducers use an Hall effect integrated circuit. The magnetic flux density B, contributing to the rise of the Hall voltage, is generated by the primary current \mathbf{I}_p to be measured. The current to be measured \mathbf{I}_p is supplied by a current source i.e. battery or generator (Fig. 1).

Within the linear region of the hysteresis cycle, B is proportional to:

B
$$(I_D)$$
 = constant $(a) \times I_D$

The Hall voltage is thus expressed by:

$$\mathbf{V}_{H} = (\mathbf{R}_{H}/\mathbf{d}) \times \mathbf{I} \times \text{constant (a)} \times \mathbf{I}_{P}$$

Except for \boldsymbol{I}_{p} all terms of this equation are constant. Therefore:

$$V_{_{\rm H}}$$
 = constant (b) \times $I_{_{\rm P}}$

The measurement signal $\mathbf{V}_{\rm H}$ amplified to supply the user output voltage or current.

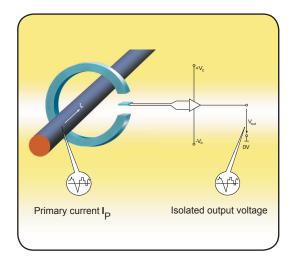
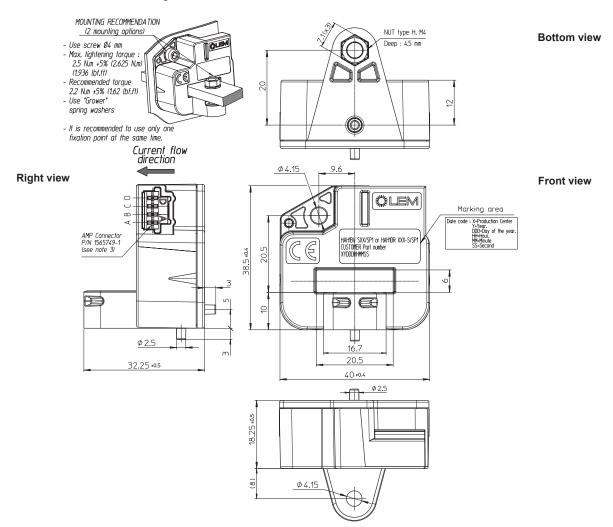


Fig. 1: Principle of the open loop transducer



HAH1DR 400-S/SP1

Dimensions HAH1DR family (in mm. 1mm = 0.0394 inch)



Bill of materials

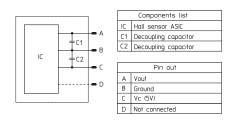
 Plastic case PBT GF 30 Magnetic core Iron silicon alloy Pins Brass gold platted

39 g Mass

Remarks

• $V_{OUT} > \frac{V_c}{2}$ when I_p flows in the direction of the arrow.

System architecture

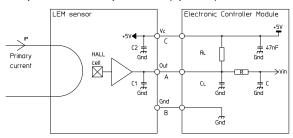


System architecture (example)

R₁ > 10 kW optional resistor for signal line diagnostic

V _{OUT}	Diagnosis	
Open circuit	V _{IN} = V _C	
Short GND	V _{IN} = OV	

 $f C_L$ < 100 nF EMC protection $f R_C$ Low pass filter EMC protection (optional)



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Absolute maximum ratings

	Cumbal	Heit	Specification			O and distance
	Symbol	ool Unit	Min	Тур	Max	Conditions
Electrical Data						
Maximum primary current peak	I _{Pmax}				1)	
Supply continuous over voltage	V				7	No operating
Reverse voltage 2)	v _c		-0.5			1 min @ T _A = 25°C
Output over voltage (continuous)	V _{OUT}	V	-0.5		V _c + 0.5	
Continuous output current	I _{OUT}	mA	-10		10	
Output short-circuit duration	T _c	min			2	
Rms voltage for AC isolation test	V _d	kV			2	50 Hz, 1 min
Isolation resistance	R _{IS}	ΜΩ	500			500 V - ISO 16750-2
Electrostatic discharge voltage	V _{ESD}	kV			2	JESD22-A114-B
Ambient storage temperature	T _s	°C	-55		125	

Operating characteristics

		Unit	Specification			0
	Symbol Unit		Min	Тур	Max	Conditions
			Electrica	Data		
Primary current	I _P	Α	-400		400	
Calibration current	I _{CAL}	Α	-400		400	@ T _A = 25°C
Supply voltage	V _c	V	4.75	5.00	5.25	
Output voltage (Analog) 3)	V _{OUT}	V	V _{OUT} = (V _c /5) X (2.5 -	+ G X I _P)	@ V _c
Sensitivity 3)	G	mV/A		5		@ V _C = 5 V
Current consumption	I _c	mA		15	20	@ V _C = 5 V, @ - 40°C < T° < 125°C
Load resistance	$R_{\scriptscriptstyle L}$	kΩ	10			
Output internal resistance	R _{OUT}	Ω			10	DC to 1 kHz
Capacitive loading	C _∟	nF	1		100	
Ambient operating temperature	T _A	°C	-40		125	Connector limited 105°C
Output drift versus power supply	V _{OUT PS}	%		0.5		
			Performan	ce Data		
Sensitivity error	$\epsilon_{_{ m G}}$	%	-1.0	± 0.5	1.0	@ T _A = 25°C @ I = I _P
Electrical offset current	I _{OE}			± 0.8		@ $T_A = 25^{\circ}C$, @ $V_C = 5 \text{ V}$
Magnetic offset current	I _{OM}	Α		± 1		$\textcircled{\mathbf{T}}_{A}$ = 25°C, $\textcircled{\mathbf{V}}_{C}$ = 5 V, after \pm \mathbf{I}_{P}
Global offset current	I _o		-2.2		2.2	@ T _A = 25°C
Average temperature coefficient of $\mathbf{V}_{\scriptscriptstyle{\mathrm{OE}}}$	TCV _{OE AV}	mV/°C	-0.08	± 0.03	0.08	@ - 40°C < T° < 125°C
Average temperature coefficient of G	TCG _{AV}	%/°C	-0.035	± 0.02	0.035	@ - 40°C < T° < 125°C
Linearity error	$\epsilon_{\scriptscriptstyle L}$	%	-1		1	$@V_{C} = 5 V @, T_{A} = 25^{\circ}C, @I = I_{P}$
Response time to 90 % of I _{PN} step	t,	μs		6	10	@ di/dt = 100 A/µs
Frequency bandwidth 4)	BW	kHz		30		@ -3 dB
Output clamping voltage min	V	V			0.1	@ V _C = 5 V, T _A = 25°C
Output clamping voltage max	\mathbf{V}_{sz}	\ \ \ \	4.9			@ V _C = 5 V, T _A = 25°C
Output voltage noise peak-peak	V _{no pp}	mV			20	DC to 1MHz

Notes:

- ¹⁾ Busbar temperature must be below 150°C
- ²⁾ Transducer not protected against reverse polarity.
 ³⁾ The output voltage \mathbf{V}_{OUT} is fully ratiometric. The offset and sensitivity are dependent on the supply voltage \mathbf{V}_{C} relative to the following formula:

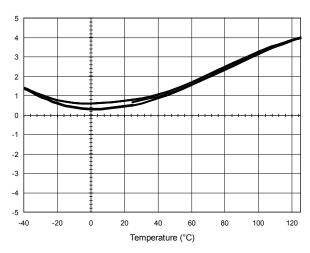
$$I_{\text{P}} = \left(V_{\text{OUT}} - \frac{V_{\text{c}}}{2}\right) \times \frac{1}{G} \times \frac{5}{V_{\text{c}}} \qquad \text{with G in (V/A)}$$

⁴⁾ Tested only with small signal only to avoid excessive heating of the magnetic core.

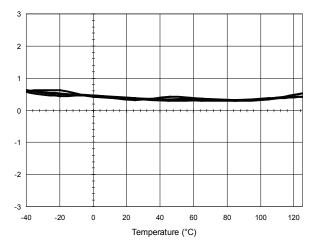


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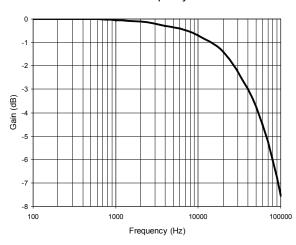
HAH1DR 400/SP1 Sensitivity error (%)



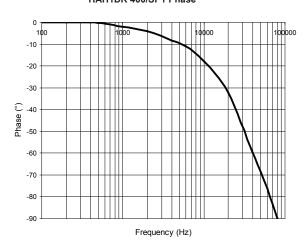
HAH1DR 400/SP1 Electrical offset error (A)



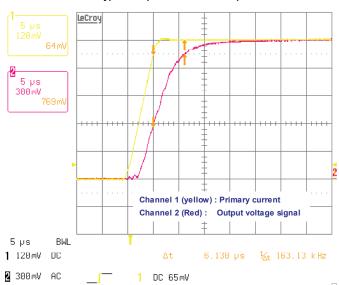
HAH1DR 400/SP1 Frequency bandwith



HAH1DR 400/SP1 Phase



Typical response time at 100 A/ μ S





HAH1DR 400-S/SP1 PERFORMANCES PARAMETERS DEFINITIONS

Output noise voltage:

The output voltage noise is the result of the noise floor of the Hall elements and the linear $I_{\rm C}$ amplifier sensitivity.

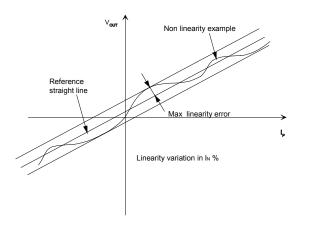
Magnetic offset:

The magnetic offset is the consequence of an over-current on the primary side. It's defined after an excursion of $I_{P\,max}$.

Linearity:

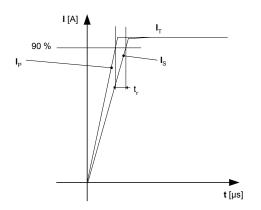
The maximum positive or negative discrepancy with a reference straight line $V_{OUT} = f(I_p)$.

Unit: linearity (%) expressed with full scale of I_{p} max. Linearity is measured on cycle + I_{p} , O, - I_{p} , O, + I_{p} without magnetic offset (average values used)



Response time (delay time) t.:

The time between the primary current signal and the output signal reach at 90 % of its final value



Typical:

Theorical value or usual accuracy recorded during the production.

Sensitivity:

The Transducer's sensitivity **G** is the slope of the straight line $V_{out} = f(I_p)$, it must establish the relation:

 $V_{out}(I_p) = V_c/5 (G \times I_p + 2.5) (*)$

(*) For all symetrics transducers.

Offset with temperature:

The error of the offset in the operating temperature is the variation of the offset in the temperature considered with the initial offset at 25° C.

The offset variation I_{OT} is a maximum variation the offset in the temperature range:

 $I_{OT} = I_{OE} \max - I_{OE} \min$

The Offset drift \mathbf{TCI}_{OEAV} is the \mathbf{I}_{OT} value divided by the temperature range.

Sensitivity with temperature:

The error of the sensitivity in the operating temperature is the relative variation of sensitivity with the temperature considered with the initial offset at 25° C.

The sensitivity variation $\mathbf{G}_{\scriptscriptstyle T}$ is the maximum variation (in ppm or %) of the sensitivity in the temperature range:

 $\mathbf{G}_{\scriptscriptstyle T}$ = (Sensitivity max - Sensitivity min) / Sensitivity at 25°C.

The sensitivity drift \mathbf{TCG}_{AV} is the \mathbf{G}_{T} value divided by the temperature range.

Offset voltage @ $I_p = 0$ A:

Is the output voltage when the primary current is null. The ideal value of \mathbf{V}_{O} is $\mathbf{V}_{\text{C}}/2$ at $\mathbf{V}_{\text{C}}=5$ V. So, the difference of \mathbf{V}_{O} - $\mathbf{V}_{\text{C}}/2$ is called the total offset voltage error. This offset error can be attributed to the electrical offset (due to the resolution of the ASIC quiescent voltage trimming), the magnetic offset, the thermal drift and the thermal hysteresis.

Environmental test specifications

Name	Standard	Conditions		
Damp heat, steady state	JESD22-A101	85°C - 85°C / 1000h		
Isolation resistance	ISO 16750-2 § 4.10	500 V/1min		
Temperature humidity cycle test	ISO 16750-4	-10 + 85°C 10 days		
Isolation test	IEC 60664-1	2 kV/50 Hz/1min		
	Mechanical tests			
Vibration test (random)	IEC 60068-2-64 ISO 16750-3 & 4.1.2.5 (2007)	20 2000 Hz Random rms (11g rms) 8h/axis		
Terminal strength test	According to LEM			
Thermal shocks	IEC 60068-214 Na	-40 + 125°C 300 cycles		
Free fall	ISO 16750-3 § 4.3	1m concrete ground		
	EMC Test			
Radiated electronagnetic immunity	Directive 2004/104/CE ISO 11452-2	30 V/m 20-2000 MHz		
Bulk current injection immunity	Directive 2004/104/CE ISO 11452-4	1-400 MHz-60mA		
Radiated radio frequency electromagnetic field immunity	IEC 61000-4-3	80 MHz to 1.000 MHz-10V/m		
Electrostatic discharge immunity test	IEC 61000-4-2	Air discharge=2 kV		